

# AO8830



# **Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor**

# **General Description**

The AO8830 uses advanced trench technology to provide excellent  $R_{\rm DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V  $V_{\rm GS(MAX)}$  rating. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its commondrain configuration. Standard Product AO8830 is Pbfree (meets ROHS & Sony 259 specifications). AO8830L is a Green Product ordering option. AO8830 and AO8830L are electrically identical.

#### **Features**

 $V_{DS}(V) = 20V$ 

 $I_D = 6 A (V_{GS} = 10V)$ 

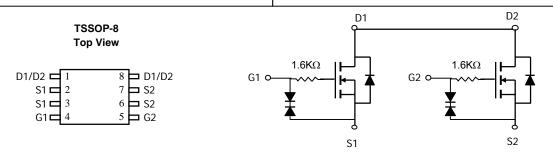
 $R_{DS(ON)}$  < 27m $\Omega$  (V<sub>GS</sub> = 10V)

 $R_{DS(ON)}$  < 30m $\Omega$  (V<sub>GS</sub> = 4.5V)

 $R_{DS(ON)}$  < 41m $\Omega$  ( $V_{GS}$  = 2.5V)

 $R_{DS(ON)} < 55m\Omega (V_{GS} = 1.8V)$ 

ESD Rating: 2000V HBM



Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		$V_{DS}$	20	V			
Gate-Source Voltage		$V_{GS}$	±12	V			
Continuous Drain	T <sub>A</sub> =25°C		6				
Current <sup>A</sup>	T <sub>A</sub> =70°C	$I_D$	4.8	Α			
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	30				
	T <sub>A</sub> =25°C	D	1.5	W			
Power Dissipation A	T <sub>A</sub> =70°C	$-P_D$	0.94	VV			
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150	°C			

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	Ь	64	83	°C/W			
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	$R_{\thetaJA}$	115	140	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	70	85	°C/W			

## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
STATIC F	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V				1	
		T <sub>J</sub> =55				5	μА
$I_{GSS}$	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V			10	
$BV_{GSO}$	Gate-Source Breakdown Voltage	V <sub>DS</sub> =0V, I <sub>G</sub> =±250uA		±12			V
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> =1mA		0.5	0.6	1	V
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =5V		30			Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =6A			22	27	mΩ
			T <sub>J</sub> =125°C		31		
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A			25	30	mΩ
		$V_{GS}$ =2.5V, $I_D$ =4A			32	41	mΩ
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =2A		42	55	mΩ	
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_{D}$ =6A			21		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.75	1	V
Is	Maximum Body-Diode Continuous Current					2.5	Α
	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, f=1MHz			290		pF
Coss	Output Capacitance				120		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				40		pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			1.6		kΩ
SWITCHI	NG PARAMETERS						
$Q_g$	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =6A			5.2		nC
$Q_{gs}$	Gate Source Charge				2.1		nC
$Q_{gd}$	Gate Drain Charge				1.9		nC
t <sub>D(on)</sub>	Turn-On DelayTime	$V_{GS}$ =4.5V, $V_{DS}$ =10V, $R_L$ =1.7 $\Omega$ , $R_{GEN}$ =3 $\Omega$			280		ns
t <sub>r</sub>	Turn-On Rise Time				972		ns
$t_{D(off)}$	Turn-Off DelayTime				2.35		μS
t <sub>f</sub>	Turn-Off Fall Time				2.2		μS
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =6A, dI/dt=100A/μs, V <sub>GS</sub> =-9V			25		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	e I <sub>F</sub> =6A, dI/dt=100A/μs, V <sub>GS</sub> =-9V			8		nC

A: The value of  $R_{\theta,JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any given application depends on the user's specific board design. The currentand power rating is based on the  $\bowtie$  10s thermal resistance rating.

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B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using  $80\,\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

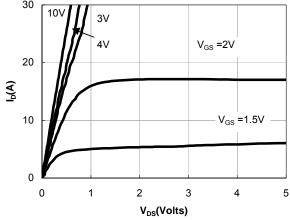


Figure 1: On-Regions CharacteristiCS

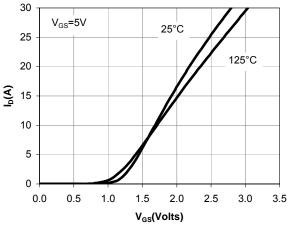


Figure 2: Transfer Characteristics

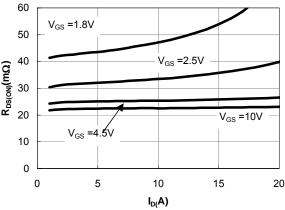


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

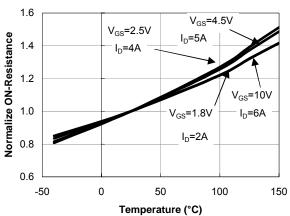


Figure 4: On-Resistance vs. Junction
Temperature

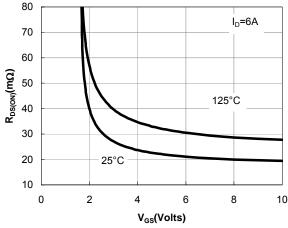


Figure 5: On-Resistance vs. Gate-Source Voltage

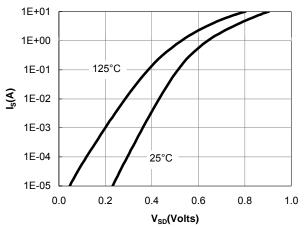
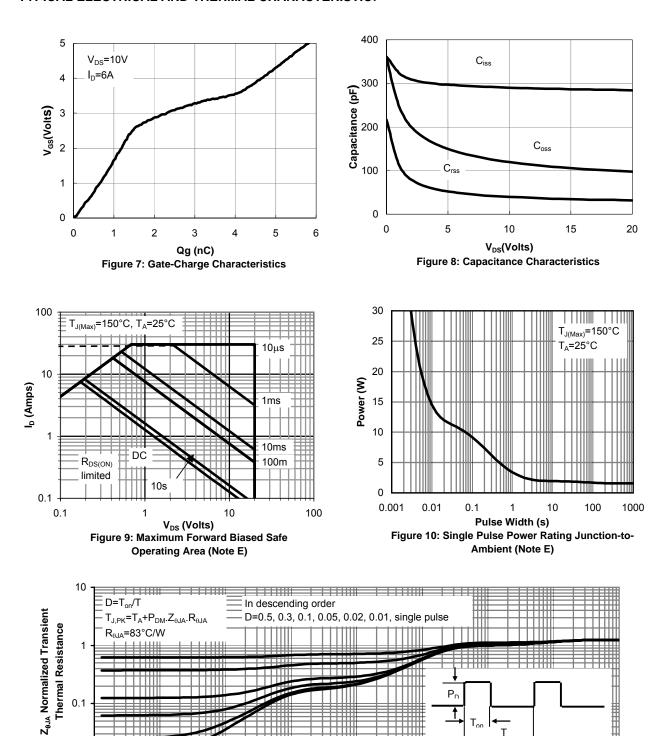


Figure 6: Body-Diode Characteristics

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Pulse Width (s) Figure 11: Normalized Maximum Transient Thermal Impedance

0.1

 $P_{\Gamma}$ 

10

100

1000

0.0001

0.001

0.01

0.1

0.01 0.00001